



US00D869305S

(12) **United States Design Patent** (10) **Patent No.:** **US D869,305 S**  
**Nasu** (45) **Date of Patent:** **\*\* Dec. 10, 2019**

- (54) **PROBE PIN**
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- (73) Assignee: **Kabushiki Kaisha Nihon Micronics,**  
Tokyo (JP)
- (\*\*) Term: **15 Years**
- (21) Appl. No.: **29/612,178**
- (22) Filed: **Jul. 28, 2017**
- (30) **Foreign Application Priority Data**  
Feb. 10, 2017 (JP) ..... 2017-002476
- (51) **LOC (12) Cl.** ..... **10-04**
- (52) **U.S. Cl.**  
USPC ..... **D10/78**
- (58) **Field of Classification Search**  
USPC ..... D10/78, 80  
CPC ..... G01R 1/06; G01R 1/067; G01R 1/06772;  
G01R 1/06777; G01R 1/06783; G01R  
1/06788; G01R 29/0878  
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

**DESCRIPTION**

FIG. 1 is a perspective view of a portion of a probe pin, showing the claimed design;  
 FIG. 2 is a front view of the probe pin;  
 FIG. 3 is a rear view of the probe pin;  
 FIG. 4 is a left side view of the probe pin;  
 FIG. 5 is a right side view of the probe pin;  
 FIG. 6 is a top plan view of the probe pin;  
 FIG. 7 is a bottom plan view of the probe pin;  
 FIG. 8 is an enlarged view of the section of the probe pin identified by the reference numbers 8-8 in FIG. 2; and,  
 FIG. 9 is an enlarged left side view of the probe pin.  
 The broken lines shown in the figures represent portions of the probe pin that form no part of the claimed design. The line-dot broken lines indicate boundary lines between the claimed portions and the disclaimed portions, and are for illustration only and form no part of the claimed design.

**1 Claim, 3 Drawing Sheets**

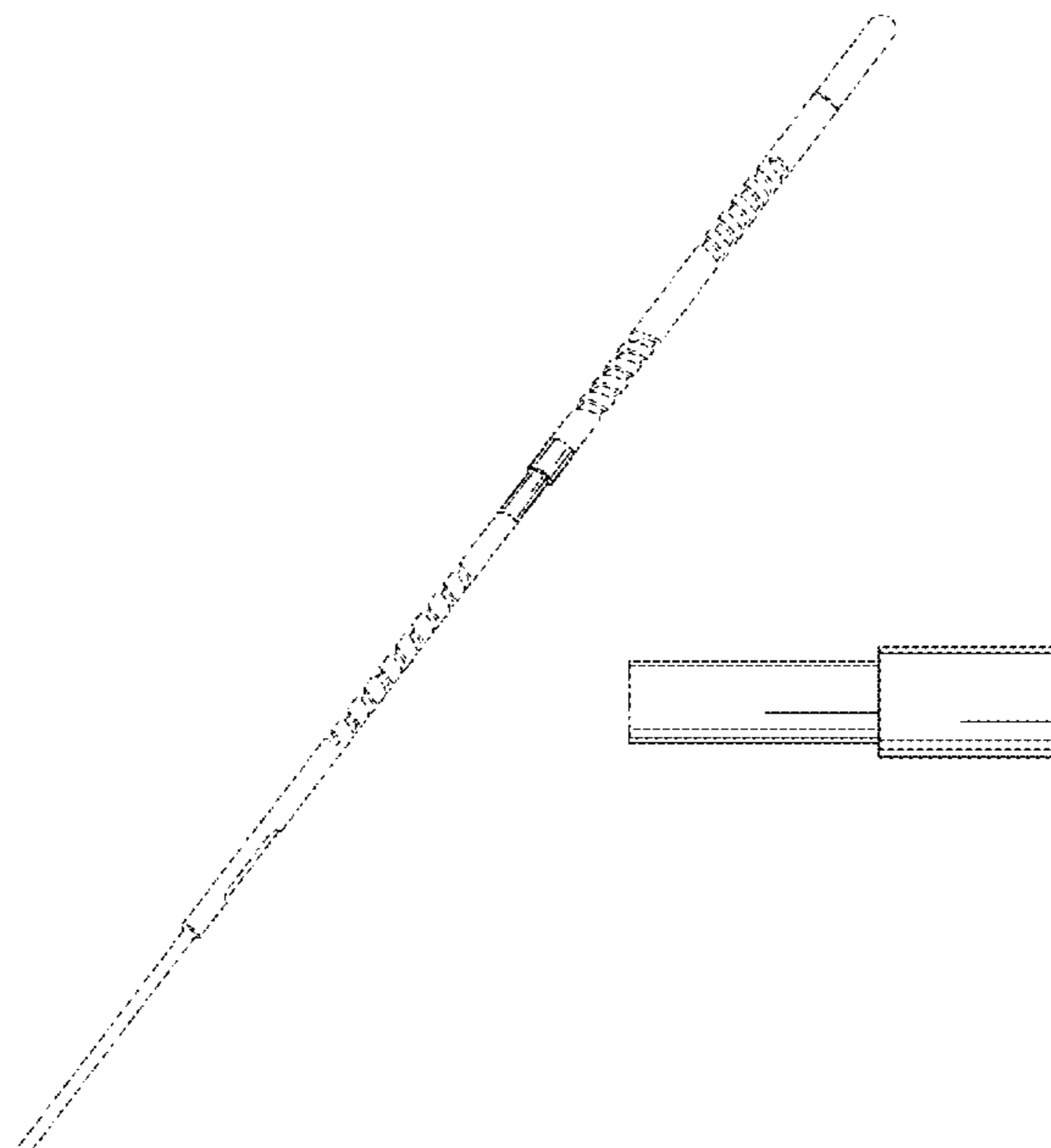


FIG.1

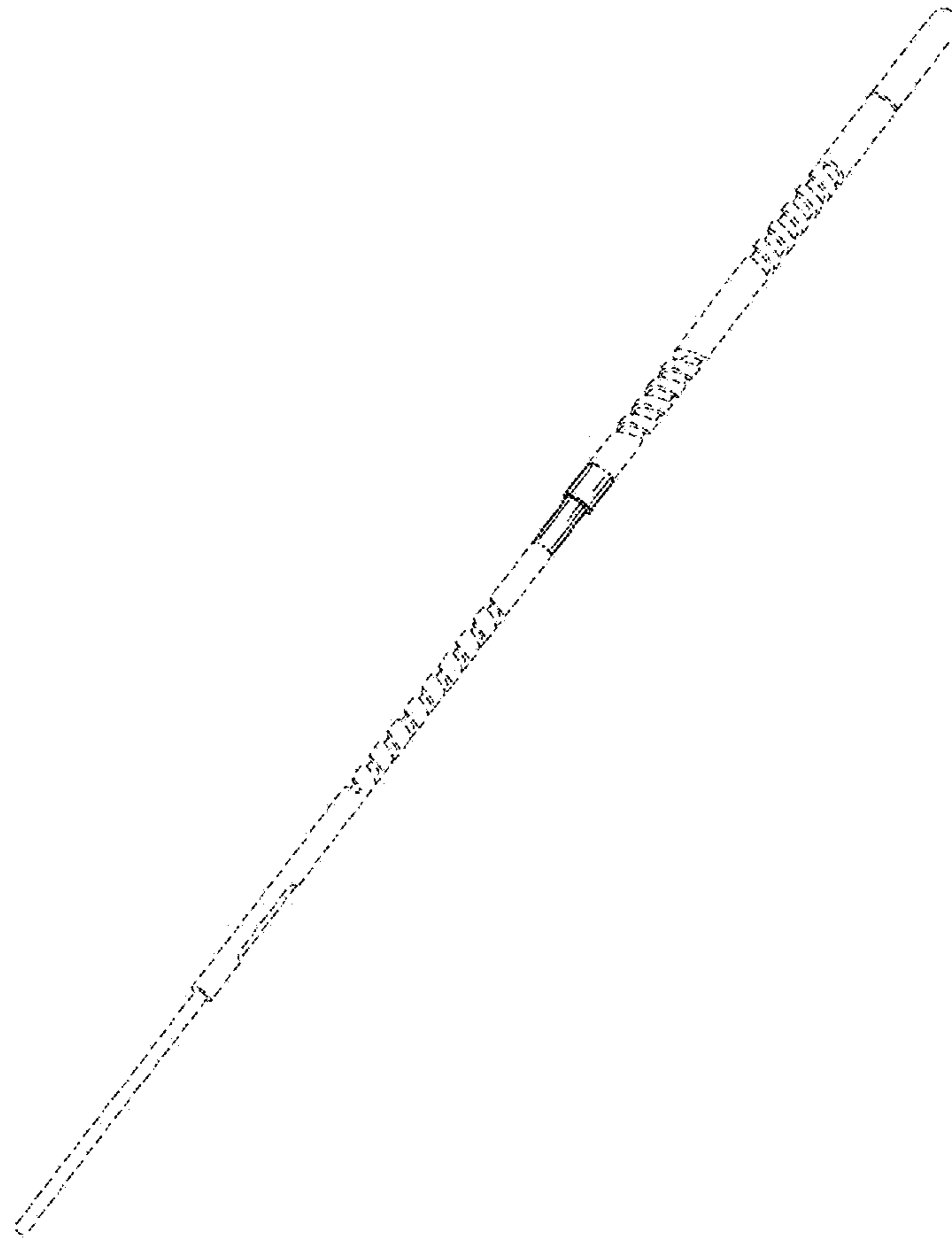


FIG.2

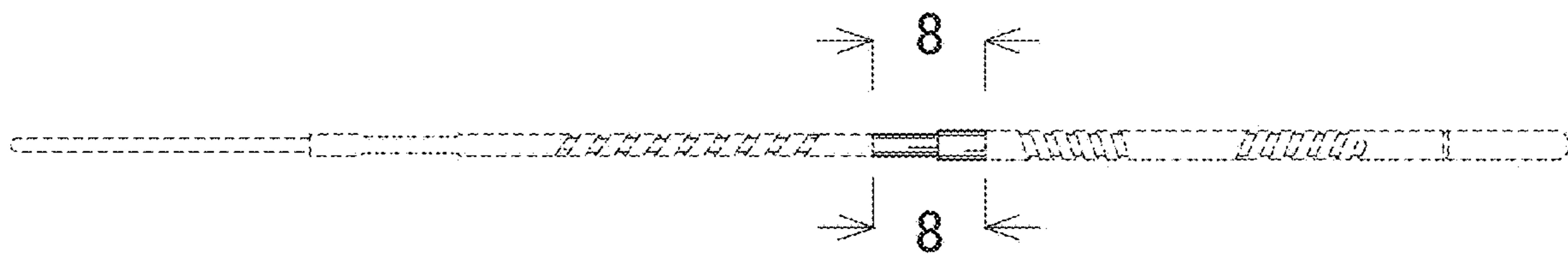


FIG.3

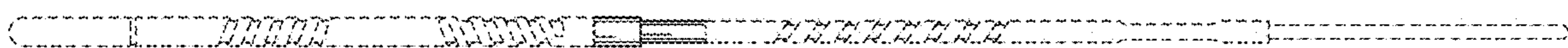


FIG.4



FIG.5



FIG.6

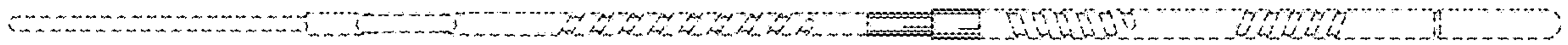


FIG.7

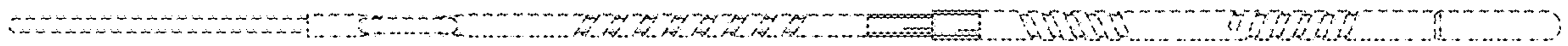


FIG.8

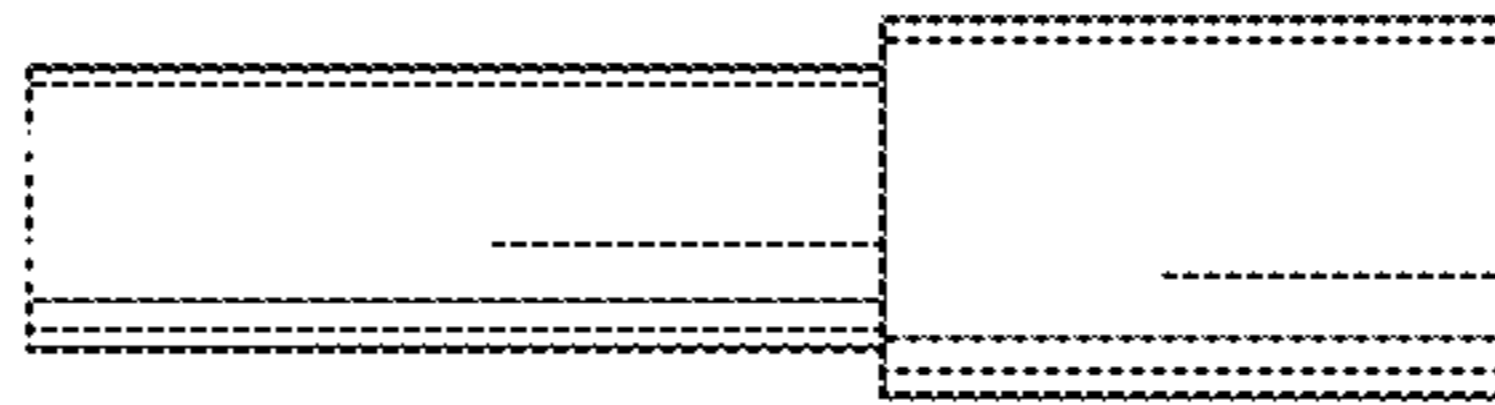


FIG.9

